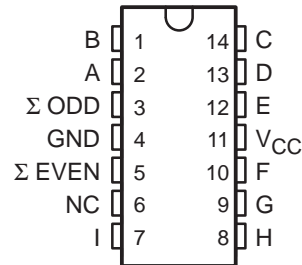- **Generates Either Odd or Even Parity for Nine Data Lines**
- **Cascadable for n-Bits Parity**
- **Flow-Through Architecture to Optimize PCB Layout**
- **Center-Pin V_{CC} and GND Configurations to Minimize High-Speed Switching Noise**
- ***EPIC***™ **(Enhanced-Performance Implanted CMOS) 1-μm Process**
- **500-mA Typical Latch-Up Immunity at 125°C**
- **Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs**

D OR N PACKAGE
(TOP VIEW)

```
          ┌───∪───┐
      B ─┤ 1    14 ├─ C
      A ─┤ 2    13 ├─ D
  Σ ODD ─┤ 3    12 ├─ E
    GND ─┤ 4    11 ├─ V_CC
 Σ EVEN ─┤ 5    10 ├─ F
     NC ─┤ 6     9 ├─ G
      I ─┤ 7     8 ├─ H
          └───────┘
```
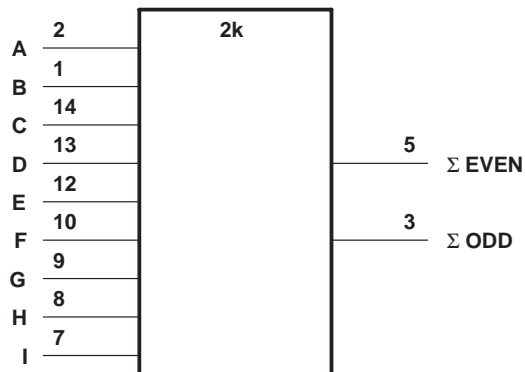
description

This universal, monolithic, nine-bit parity generator/checker features odd and even outputs to facilitate operation of either odd or even parity application. The word-length capability is easily expanded by cascading.

The 74AC11280 is characterized for operation from – 40°C to 85°C.

FUNCTION TABLE

NUMBER OF INPUTS A THRU I THAT ARE HIGH	OUTPUTS	
	Σ EVEN	Σ ODD
0, 2, 4, 6, 8	H	L
1, 3, 5, 7, 9	L	H

logic symbol†

```
          ┌──────────────┐
   A  2 ──┤  2k          │
   B  1 ──┤              │
   C 14 ──┤              │
   D 13 ──┤              │── 5  Σ EVEN
   E 12 ──┤              │
   F 10 ──┤              │── 3  Σ ODD
   G  9 ──┤              │
   H  8 ──┤              │
   I  7 ──┤              │
          └──────────────┘
```

† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

EPIC is a trademark of Texas Instruments Incorporated.

Copyright © 1993, Texas Instruments Incorporated

TEXAS INSTRUMENTS

logic diagram (positive logic)
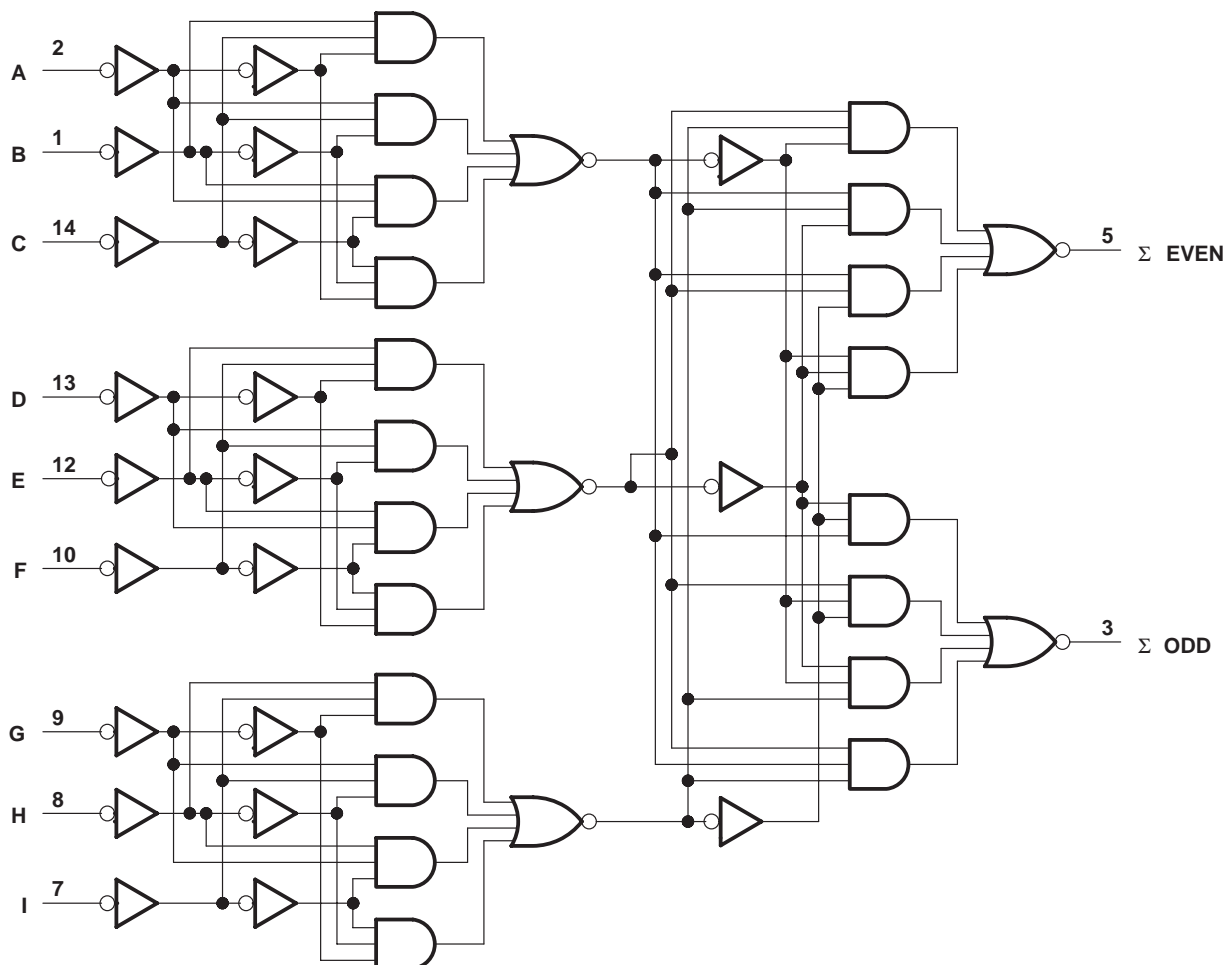
absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} .... -0.5 V to 7 V
Input voltage range, V_I (see Note 1) .... -0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Note 1) .... -0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) .... ± 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) .... ± 50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC}) .... ± 50 mA
Continuous current through V_{CC} or GND .... ± 100 mA
Storage temperature range .... $-65°C$ to $150°C$

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and
   functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not
   implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage		3	5	5.5	V
V_{IH}	High-level input voltage	V_{CC} = 3 V	2.1			V
		V_{CC} = 4.5 V	3.15			
		V_{CC} = 5.5 V	3.85			
V_{IL}	Low-level input voltage	V_{CC} = 3 V			0.9	V
		V_{CC} = 4.5 V			1.35	
		V_{CC} = 5.5 V			1.65	
V_I	Input voltage		0		V_{CC}	V
V_O	Output voltage		0		V_{CC}	V
I_{OH}	High-level output current	V_{CC} = 3 V			– 4	mA
		V_{CC} = 4.5 V			– 24	
		V_{CC} = 5.5 V			–24	
I_{OL}	Low-level output current	V_{CC} = 3 V			12	mA
		V_{CC} = 4.5 V			24	
		V_{CC} = 5.5 V			24	
$\Delta t/\Delta v$	Input transition rise or fall rate		0		10	ns / V
T_A	Operating free-air temperature		– 40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V_{CC}	T_A = 25°C			MIN	MAX	UNIT
				MIN	TYP[†]	MAX			
V_{OH}	I_{OH} = – 50 µA		3 V	2.9			2.9		V
			4.5 V	4.4			4.4		
			5.5 V	5.4			5.4		
	I_{OH} = – 4 mA		3 V	2.58			2.48		
	I_{OH} = – 24 mA		4.5 V	3.94			3.8		
			5.5 V	4.94			4.8		
	I_{OH} = – 75 mA[†]		5.5 V				3.85		
V_{OL}	I_{OL} = 50 µA		3 V			0.1		0.1	V
			4.5 V			0.1		0.1	
			5.5 V			0.1		0.1	
	I_{OL} = 12 mA		3 V			0.36		0.44	
	I_{OL} = 24 mA		4.5 V			0.36		0.44	
			5.5 V			0.36		0.44	
	I_{OL} = 75 mA[†]		5.5 V					1.65	
I_I	V_I = V_{CC} or GND		5.5 V		± 0.1			± 1	µA
I_{CC}	V_I = V_{CC} or GND,	I_O = 0	5.5 V		8			80	µA
C_i	V_I = V_{CC} or GND		5 V		3.5				pF

† All typical values are at V_{CC} = 5 V, T_A = 25°C.

TEXAS
INSTRUMENTS

74AC11280
9-BIT PARITY GENERATOR/CHECKER

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (see Figure 1)

| PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t_{PLH}	Any input	EVEN	1.5	9.8	13.5	1.5	14.9	ns
t_{PHL}			1.5	10.5	13.9	1.5	15.4	
t_{PLH}	Any input	ODD	1.5	9.9	13.8	1.5	15.1	ns
t_{PHL}			1.5	10.6	14.4	1.5	15.6	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t_{PLH}	Any input	EVEN	1.5	5.9	9.1	1.5	10.1	ns
t_{PHL}			1.5	6.7	9.9	1.5	10.9	
t_{PLH}	Any input	ODD	1.5	6	9.3	1.5	10.3	ns
t_{PHL}			1.5	6.8	10.3	1.5	11.1	

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	C_L = 50 pF, f = 1 MHz	68	pF

PARAMETER MEASUREMENT INFORMATION

LOAD CIRCUIT

VOLTAGE WAVEFORMS
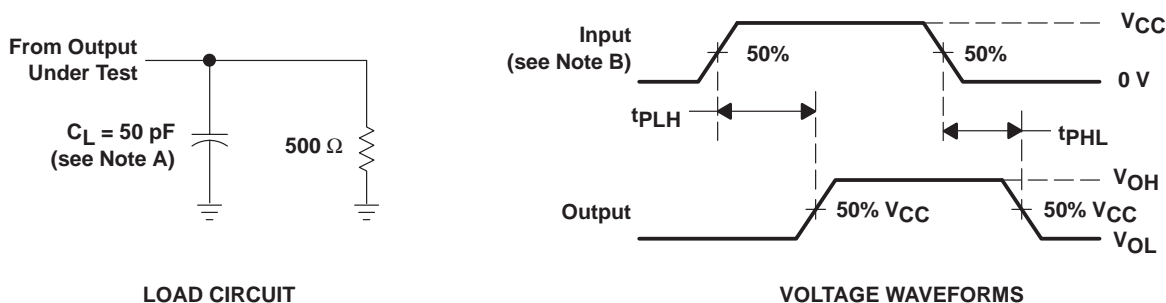
NOTES: A. C_L includes probe and jig capacitance.
B. Input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r = 3 ns, t_f = 3 ns.
C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

TEXAS
INSTRUMENTS
POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.